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Application No.	Applicant(s) KAKARALA ET AL.	
10/001,508		
Examiner	Art Unit	
Wenpeng Chen	2624	

SEARCHED				
Class	Subclass	Date	Examiner	
382	239 - 251 - 246 -			
	244	712/2/04	are	
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	248			
375	240.01			
358	426.01	-		
	426.06			
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR)	12/1/04	hne
IEEE Xplore	12/2/04	me
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